



TRW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No. : 10/809,322 Confirmation No.: 8225  
Applicant : Yoji HATA, et al.  
Filed : March 26, 2004  
TC/A.U. : 2812  
Examiner : To Be Assigned  
Docket No. : 037133.53131US  
Customer No. : 23911  
Title : Lsi Inspection Method and Defect Inspection Data Analysis Apparatus

**CLAIM OF PRIORITY UNDER 35 U.S.C. § 119**

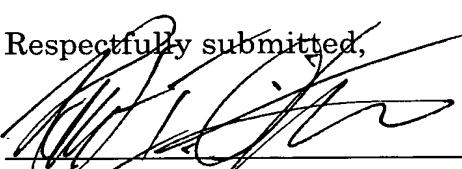
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The benefit of the filing date of prior Japanese application No. 2003-106271, filed in Japan on April 10, 2003, is hereby requested and the right of priority under 35 U.S.C. § 119 is hereby claimed.

In support of this claim, filed herewith is a certified copy of the original Japanese application.

Respectfully submitted,

  
Herbert I. Cantor  
Registration No. 24,392

July 15, 2004

CROWELL & MORING LLP  
Intellectual Property Group  
P.O. Box 14300  
Washington, DC 20044-4300  
Telephone No.: (202) 624-2500  
Facsimile No.: (202) 628-8844